



ELECTRONICS, INC.
 44 FARRAND STREET
 BLOOMFIELD, NJ 07003
 (973) 748-5089
<http://www.nteinc.com>

NTE40107B Integrated Circuit CMOS – Dual 2 Input NAND Buffer/Driver

Description:

The NTE40107B is a dual, 2–input, NAND buffer/driver in an 8–Lead DIP type package containing two independent 2–input NAND buffers with open–drain single N–Channel transistor outputs. This device features a wired–OR capability and high output sink current capability (136mA Typ. at $V_{DD} = 10V$, $V_{DS} = 1V$).

Features:

- 32 Times Standard B–Series Output Current Drive Sinking Capability:
 136mA Typ. at $V_{DD} = 10V$, $V_{DS} = 1V$
- 100% Tested for Quescent Current at 20V
- Maximum Input Current of 1 μ A at 18V Over Full Package Temperature Range; 100nA at 18V and +25°C
- 5V, 10V, and 15V Parametric Ratings
- Noise margin, Full Package Temperature Range, R_L to $V_{DD} = 10k\Omega$:
 1V at $V_{DD} = 5V$
 2V at $V_{DD} = 10V$
 2.5V at $V_{DD} = 15V$

Applications:

- Driving Relays, Lamps, and LEDs
- Line Driver
- Level Shifter (Up or Down)

Absolute Maximum Ratings:

DC Supply Voltage Range (Voltages Referenced to V_{SS} Terminal), V_{DD} –0.5V to +2.0V
 Input Voltage Range, All Inputs –0.5V to $V_{DD} + 0.5V$
 DC Input Current, Any One Input $\pm 10mA$
 Power Dissipation Per Package, P_D
 For $T_A = -55^\circ$ to $+100^\circ C$ 500mW
 For $T_A = +100^\circ$ to $+125^\circ C$ Derate Linearity at 12mW/ $^\circ C$ to 200mW
 Device Dissipation Per Output Transistor ($T_A =$ Full Package Temperature Range) 100mW
 Operating Temperature Range, T_A -55° to $+125^\circ C$
 Storage Temperature Range, T_{stg} -65° to $+150^\circ C$
 Lead Temperature (During Soldering, 1/16" from Case for 10sec Max), T_L $+265^\circ C$

Recommended Operating Conditions: (Note 1)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Supply Voltage Range	V_{DD}	$T_A = -55^\circ$ to $+125^\circ C$	3	–	18	V

Note 1. For maximum reliability, nominal operating conditions should be selected so that operation is always within the above ranges.

Dynamic Electrical Characteristics: ($T_A = +25^\circ\text{C}$, $C_L = 50\text{pF}$, Input t_r , $t_f = 20\text{ns}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit	
Propagation Delay, High-to-Low	t_{PHL}	$R_L = 120\Omega$, Note 2	$V_{DD} = 5\text{V}$	-	100	200	ns
			$V_{DD} = 10\text{V}$	-	45	90	ns
			$V_{DD} = 15\text{V}$	-	30	60	ns
Propagation Delay, Low-to-High	t_{PLH}	$R_L = 120\Omega$, Note 2	$V_{DD} = 5\text{V}$	-	100	200	ns
			$V_{DD} = 10\text{V}$	-	60	120	ns
			$V_{DD} = 15\text{V}$	-	50	100	ns
Transition Time, High-to-Low	t_{THL}	$R_L = 120\Omega$, Note 2	$V_{DD} = 5\text{V}$	-	50	100	ns
			$V_{DD} = 10\text{V}$	-	20	40	ns
			$V_{DD} = 15\text{V}$	-	10	20	ns
Transition Time, Low-to-High	t_{TLH}	$R_L = 120\Omega$, Note 2	$V_{DD} = 5\text{V}$	-	50	100	ns
			$V_{DD} = 10\text{V}$	-	35	70	ns
			$V_{DD} = 15\text{V}$	-	25	50	ns
Average Input Capacitance	C_{IN}	Any Input	-	5.0	7.5	pF	
Average Output Capacitance	C_{OUT}	Any Output	-	30	-	pF	

Note 2. R_L is external pull-up resistor to V_{DD} .

Static Electrical Characteristics:

Parameter	Symbol	Conditions			Limits at Indicated Temperatures ($^\circ\text{C}$)							Unit
		V_O (V)	V_{IN} (V)	V_{DD} (V)					+25			
					-55	-40	+85	+125	Min	Typ	Max	
Quiescent Device Current	I_{DDMax}	-	0.5	5	1	1	30	30	-	0.02	1	μA
		-	0,10	10	2	2	60	60	-	0.02	2	μA
		-	0,15	15	4	4	120	120	-	0.02	4	μA
		-	0,20	20	20	20	600	600	-	0.04	20	μA
Output Low (Sink) Current	I_{OLMin}	0.4	0,5	5	21	20	14	12	16	32	-	mA
		1	0,5	5	44	42	30	25	34	68	-	mA
		0.5	0,10	10	49	46	32	28	37	74	-	mA
		1	0,10	10	89	85	60	51	68	136	-	mA
		0.5	0,15	15	66	63	44	38	50	100	-	mA
Output High (Source) Current	I_{OHMin}	No Internal Pull-Up Devices										mA
Input Low Voltage (Note 3)	V_{ILMax}	4.5	-	5	-	1.5			-	-	1.5	V
		9	-	10	-	3.0			-	-	3.0	V
		13.5	-	15	-	4.0			-	-	4.0	V
Input High Voltage (Note 3)	V_{IHMin}	0,5,4,5	-	5	-	3.5			3.5	-	-	V
		1,9	-	10	-	7			7	-	-	V
		1,5,13,5	-	15	-	11			11	-	-	V
Input Current	I_{INMax}	-	0,18	18	± 0.1	± 0.1	± 1	± 1	-	$\pm 10^{-5}$	± 0.1	μA
Output Leakage Current	I_{OZMax}	18	0,18	18	2	2	20	20	-	10^{-4}	2	μA

Note 3. Measured with external pull-up resistor, $R_L = 10\text{k}\Omega$ to V_{DD} .

Special Considerations:

Limiting Capacitive Currents for $C_L > 500\text{pF}$, $V_{DD} > 15\text{V}$. For $V_{DD} > 15\text{V}$, and load capacitance (C_L) from output to GND $> 500\text{pF}$, an external 25Ω series limiting resistor should be inserted between the output terminal and C_L . No external resistor is necessary if $C_L < 500\text{pF}$ or $V_{DD} < 15\text{V}$.

Driving Inductive Loads. When using the NTE40107B to drive inductive loads, the load should be shunted with a diode to prevent high voltages from developing across the device output.

Truth Table:

A	B	C	
0	0	1 *	Z #
1	0	1 *	Z #
0	1	1 *	Z #
1	1	0	

* Requires external pull-up resistor (R_L) to V_{DD} .

Without pull-up resistor (3-state).

